

**Search Notes**

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Examiner

Nhan T. Tran

Applicant(s)/Patent under  
Reexamination

IIDA, TAKAYUKI

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)  Text search - see search history printout	9/21/2007	NT